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THE EMBODIMENTS OF THE INVENTION IN WHICH AN EXCLUSIVE PROPERTY OR PRIVILEGE IS CLAIMED ARE DEFINED AS FOLLOWS:

- A content addressable memory (CAM) having a plurality of ternary memory cells in a
 fabricated semiconductor material, each ternary half cell comprising:
 an equal number of transistors of a p-type and an n-type, the p-type transistors being formed in a n-well region and the n-type transistors being formed in a p-well region of said semiconductor material, the wells having at most one p+ to n+ region spacing, the transistors being interconnected to form said half ternary CAM cell and wherein the interconnections between the
 half cell are restricted to a first group of conductive layers and connections between said cell and
 - 2. A CAM as defined in claim 1, said external signal lines including a search line, matchline, bitline and word line.
 - 3. A CAM as defined in claim 2, said search line being formed in a third metal layer.

signal lines external to said cell are formed in a second group of conductive layers.

- 4. A CAM as defined in claim 3, said matchline and wordline being formed in a fourth metal layer.
- 5. A CAM as defined in claim 1, said bit line being formed in a fifth metal layer.
- 6. A CAM as defined in claim 1, said silicon layer including one polysilicon layer.
- 25 7. A content addressable memory (CAM), comprising:
 - (a) a plurality of half ternary CAM cells each having an equal number of transistors of a p-type and an n-type, the p-type transistors being formed in a first well region and the n-type transistors being formed in a second well region of a semiconductor material, the wells having at most one p+ to n+ region spacing, the transistors being interconnected to form said half ternary CAM cell and wherein the interconnections are restricted to a silicon layer and a first metal layer;

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- (b) power lines formed in a second metal layer and coupled to said cells;
- (c) a plurality of search lines formed in a third metal layer;
- (d) a plurality of wordlines and matchlines formed in a fourth metal layer, and
- (e) a plurality of bitlines formed in a fifth metal layer.